

## 650V GaN Power Transistor (FET)

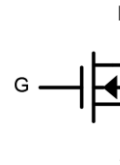
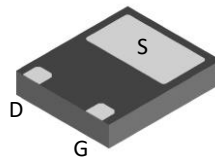
### Features

- Easy to use, compatible with standard gate drivers
- Excellent  $Q_G \times R_{DS(on)}$  figure of merit (FOM)
- Low  $Q_{RR}$ , no free-wheeling diode required
- Low switching loss
- RoHS compliant and Halogen-free

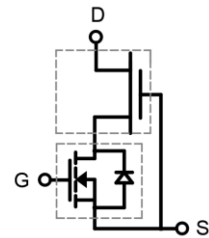
Product Summary		
$V_{DSS}$	650	V
$R_{DS(on), typ}$	240	mΩ
$Q_G, typ$	21.5	nC
$Q_{RR, typ}$	39	nC

### Applications

- High efficiency power supplies
- High efficiency USB PD adapters
- Other consumer electronics



Schematic Symbol



Cascode Device Structure

### Packaging

Part Number	Package	Packaging	Base QTY
HMN9N65Q	DFN 5 x 6	Tape and Reel	2500

### Maximum ratings, at $T_C=25^\circ\text{C}$ , unless otherwise specified

Symbol	Parameter		Limit Value	Unit
$I_D$	Continuous drain current @ $T_C=25^\circ\text{C}$		8	A
	Continuous drain current @ $T_C=100^\circ\text{C}$		5	A
$I_{DM}$	Pulsed drain current @ $T_C=25^\circ\text{C}$ (pulse width: 10us)		31	A
	Pulsed drain current @ $T_C=150^\circ\text{C}$ (pulse width: 10us)		23	A
$V_{DSS}$	Drain to source voltage ( $T_J = -55^\circ\text{C}$ to $150^\circ\text{C}$ )		650	V
$V_{TDSS}$	Transient drain to source voltage <sup>a</sup>		800	V
$V_{GSS}$	Gate to source voltage		$\pm 20$	V
$P_D$	Maximum power dissipation @ $T_C=25^\circ\text{C}$		29	W
$T_C$	Operating temperature	Case	-55 to 150	$^\circ\text{C}$
$T_J$		Junction	-55 to 150	$^\circ\text{C}$
$T_S$	Storage temperature		-55 to 150	$^\circ\text{C}$
$T_{CSOLD}$	Soldering peak temperature		260	$^\circ\text{C}$

## Thermal Resistance

Symbol	Parameter	Typical	Unit
R <sub>θJC</sub>	Junction-to-case	4.3	°C/W
R <sub>θJA</sub>	Junction-to-ambient <sup>b</sup>	50	°C/W

### Notes:

- Off-state spike duty cycle < 0.01, spike duration < 2us
- Device on one layer epoxy PCB for drain connection (vertical and without air stream cooling, with 6cm<sup>2</sup> copper area and 70μm thickness)

Electrical Parameters, at  $T_J=25^\circ\text{C}$ , unless otherwise specified

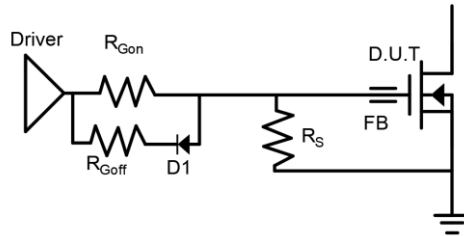
Symbol	Min	Typ	Max	Unit	Test Conditions
Forward Characteristics					
V <sub>DSS-MAX</sub>	650	-	-	V	V <sub>GS</sub> =0V
V <sub>GS(th)</sub>	1.2	1.6	2.0	V	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =500μA
R <sub>DS(on)</sub> <sup>c</sup>	190	240	312	mΩ	V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =25°C
	-	500	-		V <sub>GS</sub> =8V, I <sub>D</sub> =4A, T <sub>J</sub> =150°C
I <sub>DSS</sub>	-	8	20	μA	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C
	-	50	-	μA	V <sub>DS</sub> =700V, V <sub>GS</sub> =0V, T <sub>J</sub> =150°C
I <sub>GSS</sub>	-	-	150	nA	V <sub>GS</sub> =20V
	-	-	-150	nA	V <sub>GS</sub> =-20V
C <sub>ISS</sub>	-	500	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =650V, f=1MHz
C <sub>OSS</sub>	-	18	-	pF	
C <sub>RSS</sub>	-	2	-	pF	
C <sub>O(er)</sub>	-	25	-	pF	V <sub>GS</sub> =0V, V <sub>DS</sub> =0 - 650V
C <sub>O(tr)</sub>	-	45	-	pF	
Q <sub>G</sub>	-	21.5	-	nC	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =5.5A
Q <sub>GS</sub>	-	3	-		
Q <sub>GD</sub>	-	3.5	-		
t <sub>D(on)</sub>	-	20	-	ns	V <sub>DS</sub> =400V, V <sub>GS</sub> =0 - 12V, I <sub>D</sub> =3A, R <sub>G</sub> =30Ω
t <sub>R</sub>	-	7	-		
t <sub>D(off)</sub>	-	80	-		
t <sub>F</sub>	-	6	-		
Reverse Characteristics					
V <sub>SD</sub>	-	1.2	-	V	V <sub>GS</sub> =0V, I <sub>S</sub> =2A, T <sub>J</sub> =25°C
	-	1.7	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =25°C
	-	2	-		V <sub>GS</sub> =0V, I <sub>S</sub> =5A, T <sub>J</sub> =150°C
t <sub>RR</sub>	-	12	-	ns	I <sub>S</sub> =3A, V <sub>GS</sub> =0V, d <sub>i</sub> /d <sub>t</sub> =1000A/us, V <sub>DD</sub> =400V
Q <sub>RR</sub>	-	39	-	nC	

Notes:

c. Dynamic on-resistance; see Figure 17 and 18 for test circuit and configurations

## Circuit Implementation

Mostly used in flyback, forward and push-pull converters

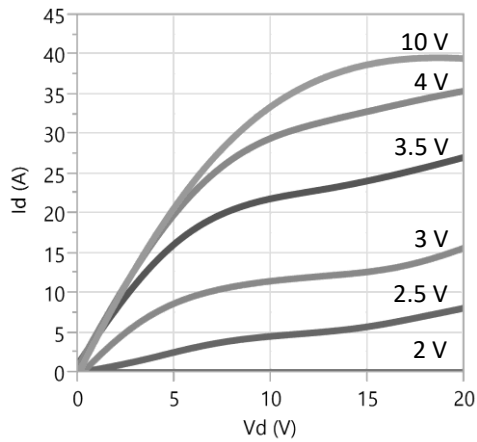


**Recommended Single Ended Drive Circuit**

Recommended gate drive: (0 V, 12 V) with  $R_{Gon} = 300 - 500 \Omega$ ,  $R_{Goff} = 10 \Omega$

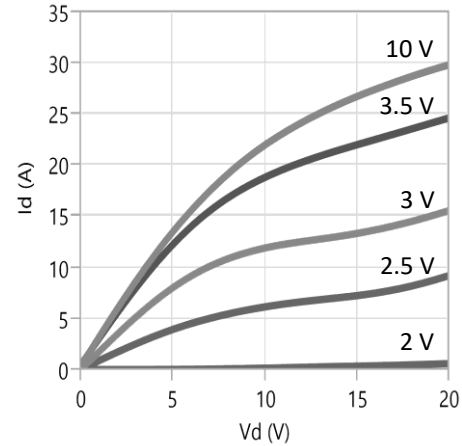
Gate Ferrite Bead (FB)	Gate Resistance ( $R_{Gon}$ )	Gate Resistance ( $R_{Goff}$ )	Gate Source Resistance ( $R_S$ )	Gate Diode (D1)
300 - 600 $\Omega$ @100 MHz	300 - 500 $\Omega$	10 $\Omega$	10 k $\Omega$	1N4148

Typical Characteristics, at  $T_C=25^\circ\text{C}$ , unless otherwise specified



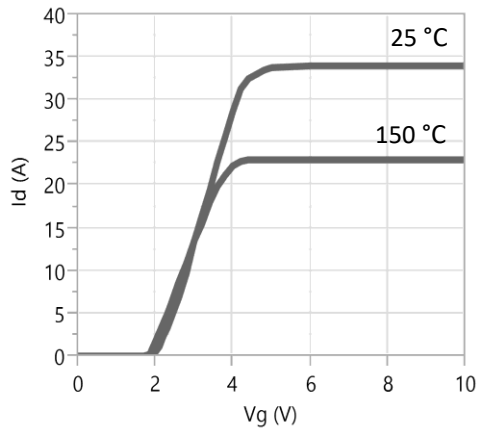
**Figure 1. Typical Output Characteristics  $T_j=25^\circ\text{C}$**

Parameter:  $V_{GS}$



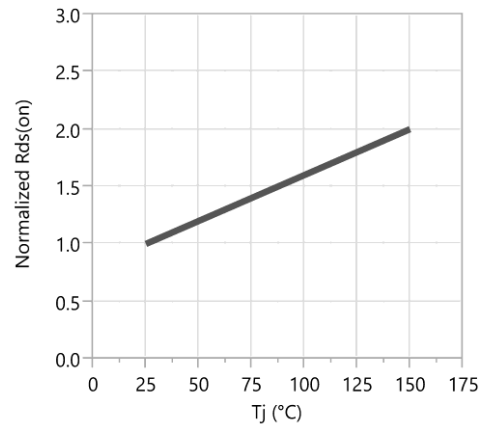
**Figure 2. Typical Output Characteristics  $T_j=150^\circ\text{C}$**

Parameter:  $V_{GS}$



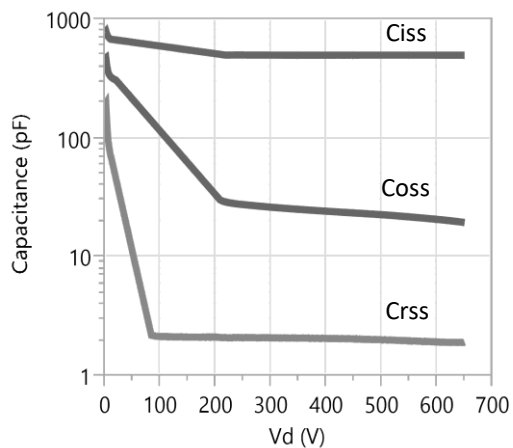
**Figure 3. Typical Transfer Characteristics**

$V_{DS}=10\text{V}$ , Parameter:  $T_j$



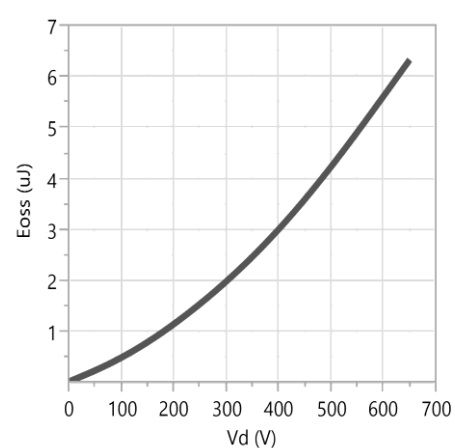
**Figure 4. Normalized On-resistance**

$I_D=4\text{A}$ ,  $V_{GS}=8\text{V}$



**Figure 5. Typical Capacitance**

$V_{GS}=0\text{V}$ ,  $f=1\text{MHz}$



**Figure 6. Typical  $C_{oss}$  Stored Energy**

Typical Characteristics, at  $T_C=25^\circ\text{C}$ , unless otherwise specified

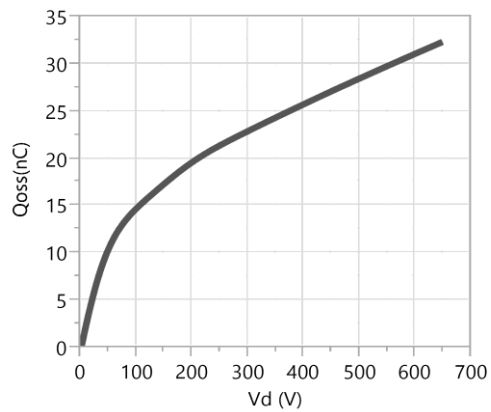


Figure 7. Typical Qoss

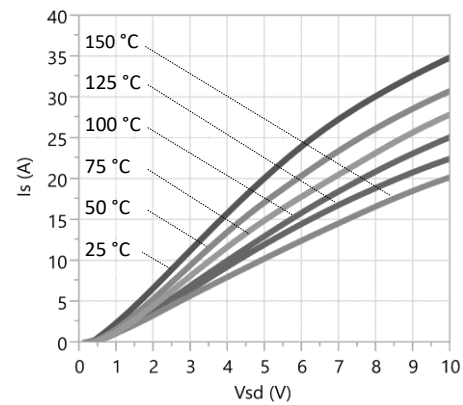


Figure 8. Forward Characteristic of Rev. Diode

$I_s=f(V_{sd})$ , Parameter  $T_j$

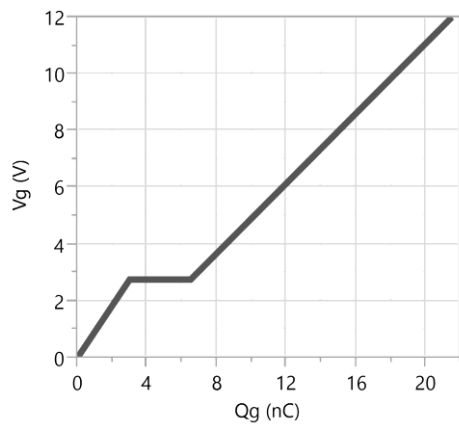


Figure 9. Typical Gate Charge

$I_{DS}=5.5\text{A}$ ,  $V_{DS}=400\text{V}$

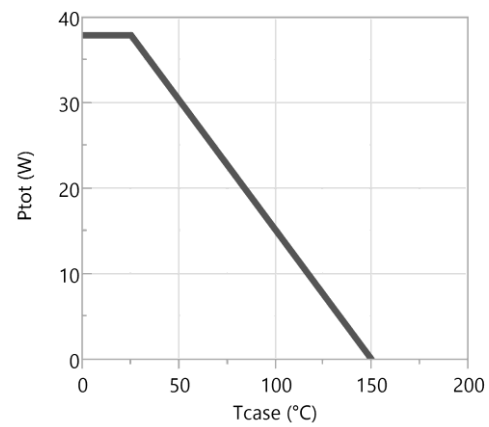


Figure 10. Power Dissipation

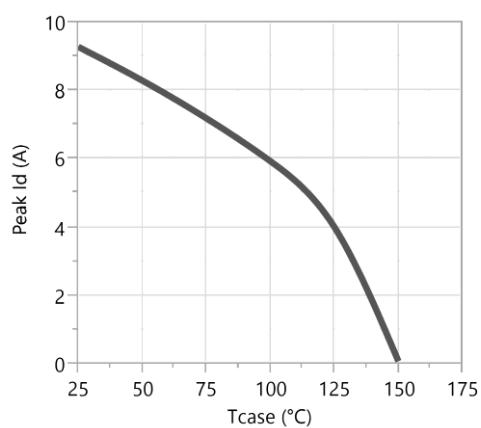


Figure 11. Current Derating

Typical Characteristics, at  $T_C=25^\circ\text{C}$ , unless otherwise specified

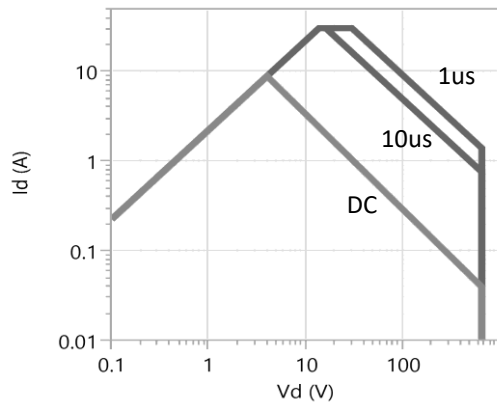


Figure 12. Safe Operating Area  $T_C=25^\circ\text{C}$

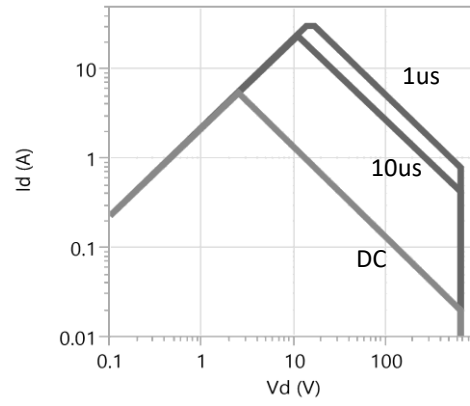


Figure 13. Safe Operating Area  $T_C=80^\circ\text{C}$

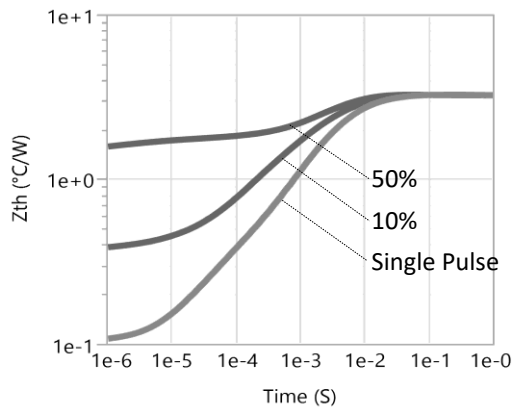


Figure 14. Transient Thermal Resistance

## Test Circuits and Waveforms

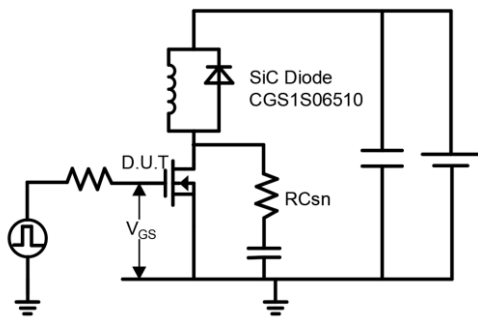


Figure 15. Switching Time Test Circuit

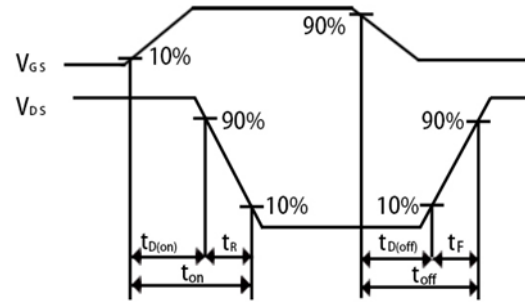


Figure 16. Switching Time Waveform

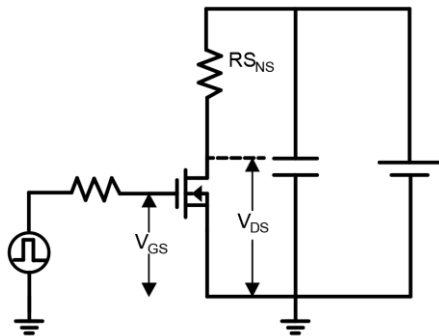


Figure 17. Dynamic  $R_{DS(on)}$  Test Circuit

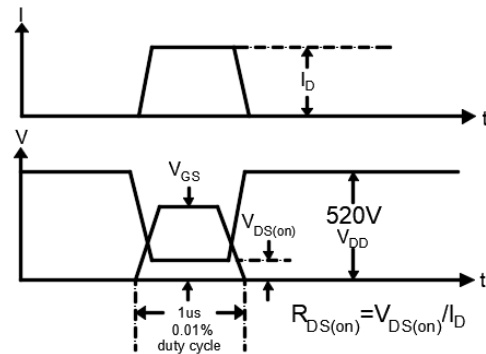


Figure 18. Dynamic  $R_{DS(on)}$  Waveform

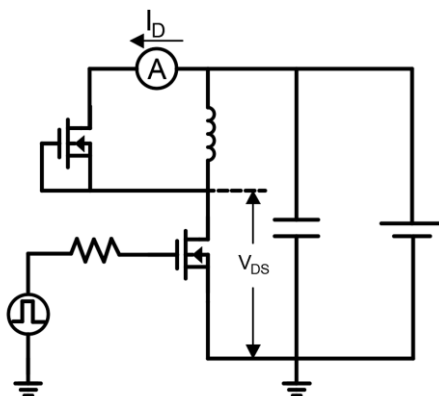


Figure 19. Diode Characteristic Test Circuits

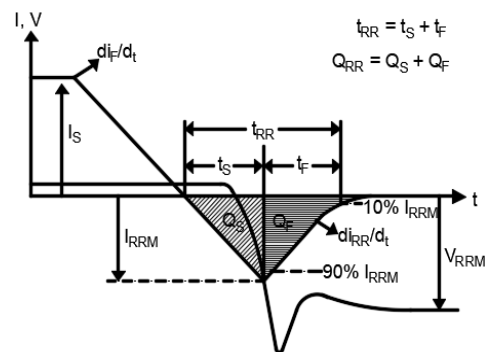


Figure 20. Diode Recovery Waveform



## Design Considerations

Fast switching GaN device can reduce power conversion losses, and thus enable high frequency operations. Certain PCB design rules and instructions, however, need to be followed to take full advantages of fast switching GaN devices.

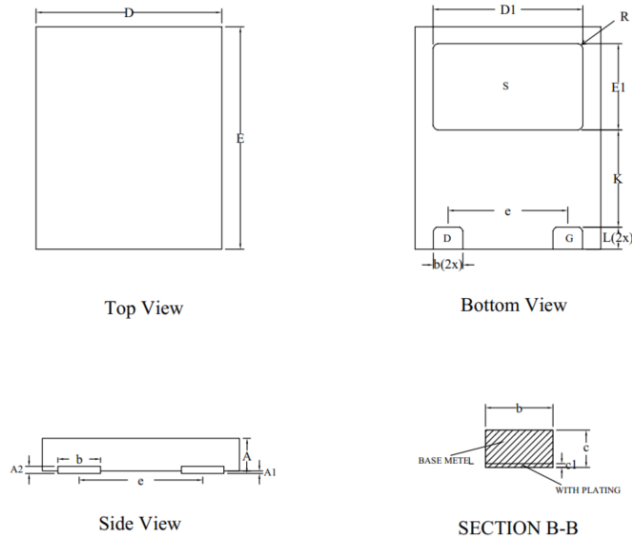
Before evaluating H&M Semi's GaN devices, please refer to the table below which provides some practical rules that should be followed during the evaluation.

**When Evaluating H&M Semi 's GaN Devices:**

DO	DO NOT
Make sure the traces are as short as possible for both drive and power loops to minimize parasitic inductance	Using H&M Semi 's devices in GDS board layouts
Use the test tool with the shortest inductive loop, and make sure test points should be placed close enough	Use differential mode probe or probe ground clip with long wires
Minimize the lead length of DFN 8*8mm packages when installing them to PCB	Use long traces in drive circuit, or long lead length of the devices

## Package Outline

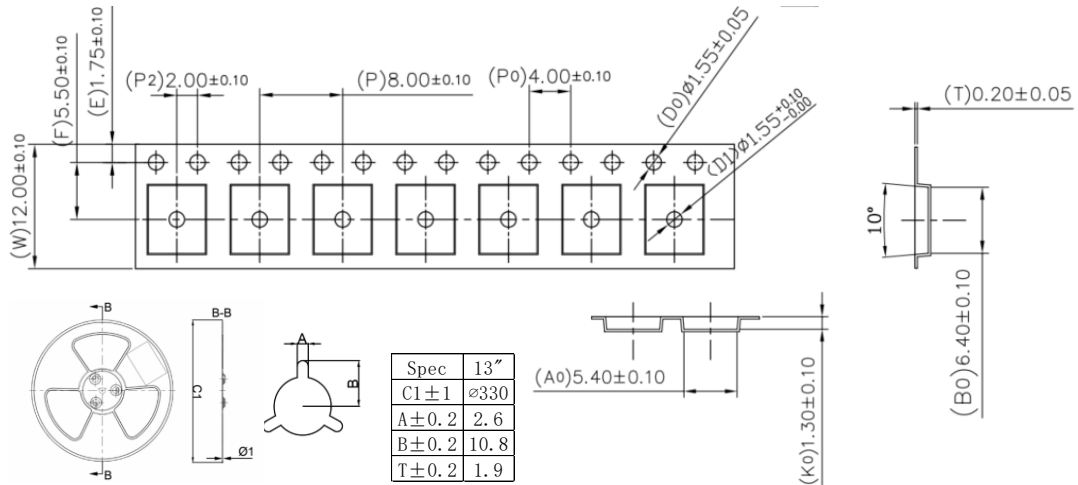
## DFN 5 x 6mm (MS) Package



Symbol	Millimeter		
	Min	Nom	Max
A	0.85	1.00	1.15
A1	0.00	-	0.05
A2	-	0.20	0.22
b	0.82	0.87	0.92
c	-	0.20	-
c1	0.01	-	0.02
D	4.90	5.00	5.10
D1	4.09	4.24	4.39
E	5.90	6.00	6.10
E1	2.15	2.30	2.45
e	3.37BSC		
K	2.50	-	-
L	0.71	0.81	0.91
R	-	0.13	-

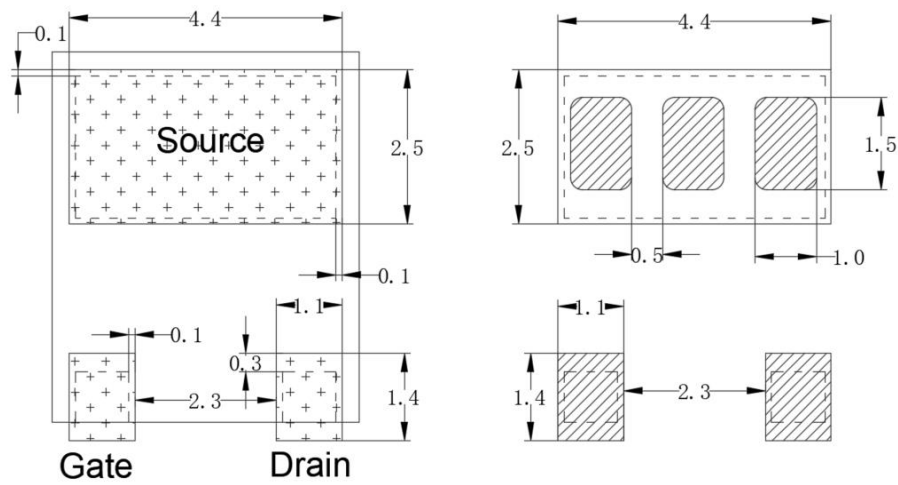
## Tape and Reel Information



Dimensions are shown in millimeters



## Recommended PCB Layout & Metal mask opening

Dimensions are shown in millimeters



 Chip electrodes
  PCB layout
  Metal mask opening

## Revision History

Version	Date	Change(s)
1.0	06/24/2022	Released Formal datasheet